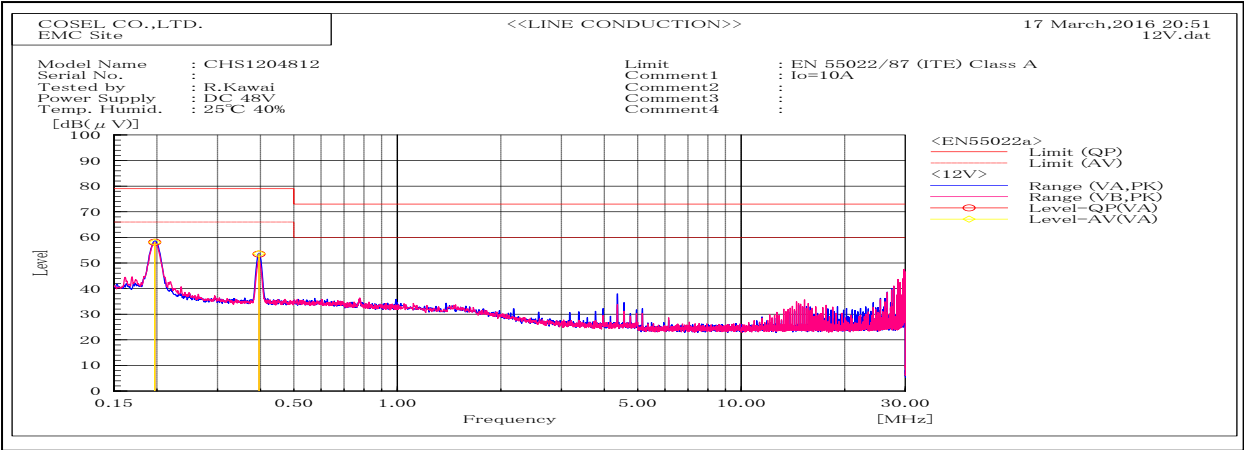
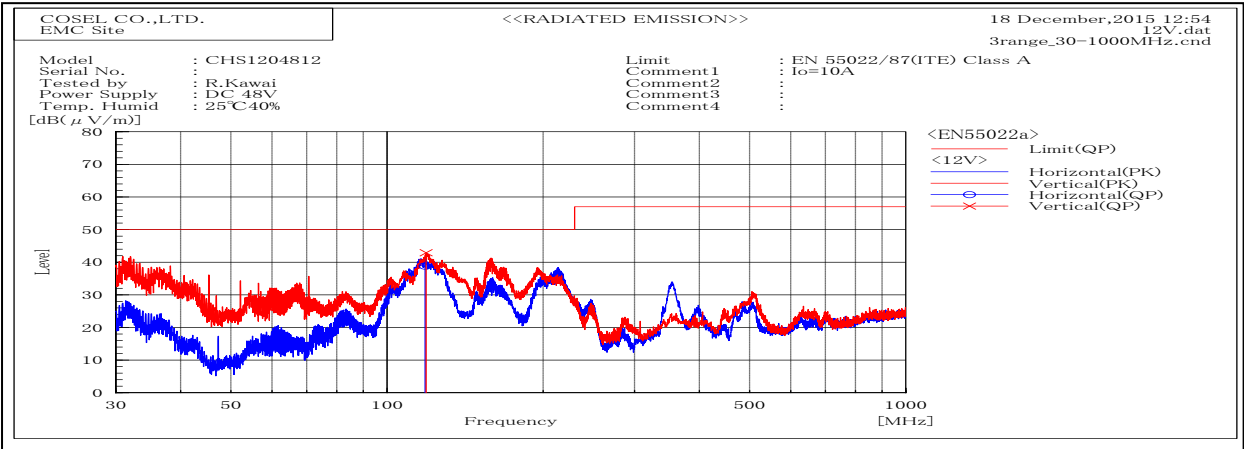


DATA SHEET		Date	06-May-16
Model	CHS1204812	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	R.Kawai



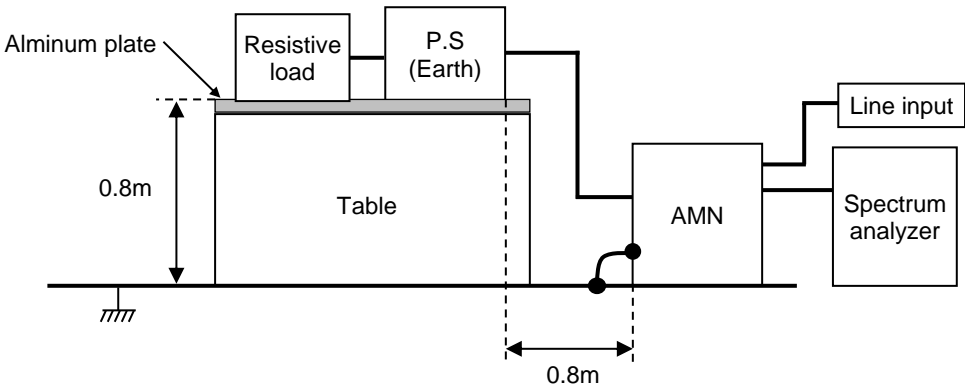
Frequency MHz	Harm	Line Phase	Reading dB(μV)		Factor dB	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/ Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.197		VA	38.0	37.9	20.1	58.1	58.0	79.0	66.0	20.9	8.0	Pass	
0.396		VA	33.5	33.3	20.0	53.5	53.5	79.0	66.0	25.5	12.5	Pass	



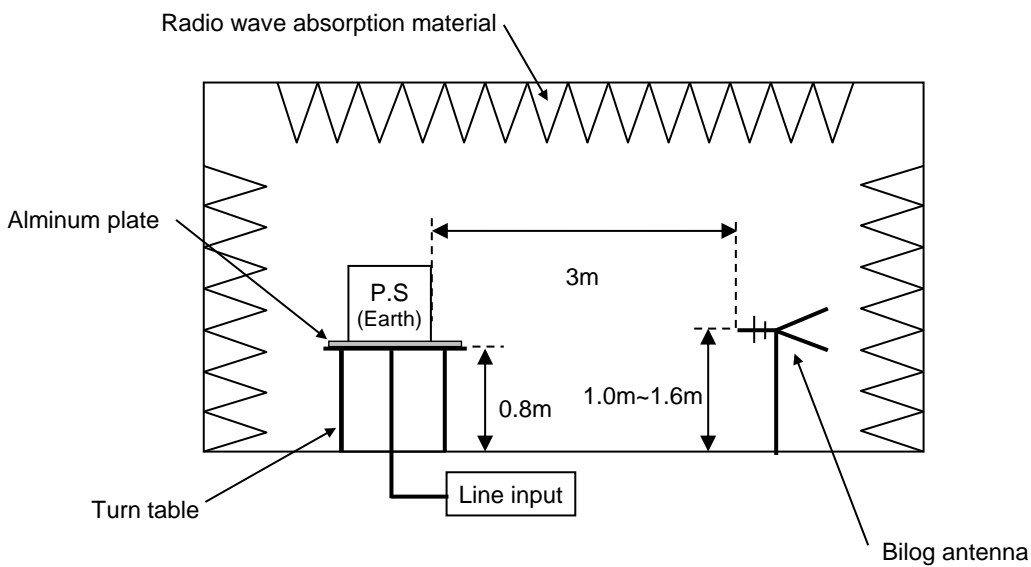
Frequency MHz	Harm	Polarization	Stability	Reading dB(μV)		Factor dB(1/m)	Level dB(μV/m)		Limit dB(μV/m)	Margin dB	Pass/ Fail	Height cm	Angle deg	Remark
				QP	AV		QP	AV						
118.395		H	Stable	58.1	-19.3		38.8		50.0	11.2	Pass	138.0	30.0	
118.916		V	Stable	59.8	-16.9		42.9		50.0	7.1	Pass	105.0	165.0	

DATA SHEET		Date	06-May-16
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	R.Kawai

1. Line conduction



2. Radiated emission



## Conditions

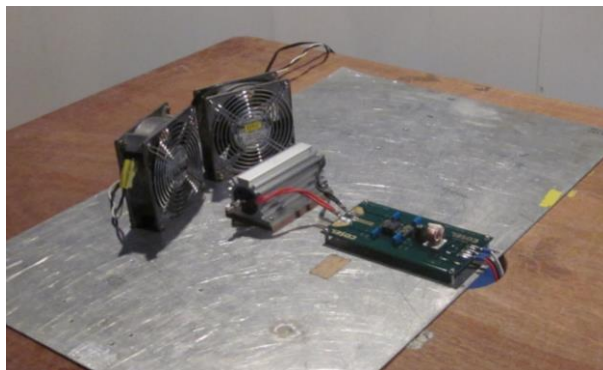
Test : EMI  
Model Name : CHS12048□

○Photographs of Test Set-Up

### LINE CONDUCTION



### RADIATED EMISSION



○Testing circuitry

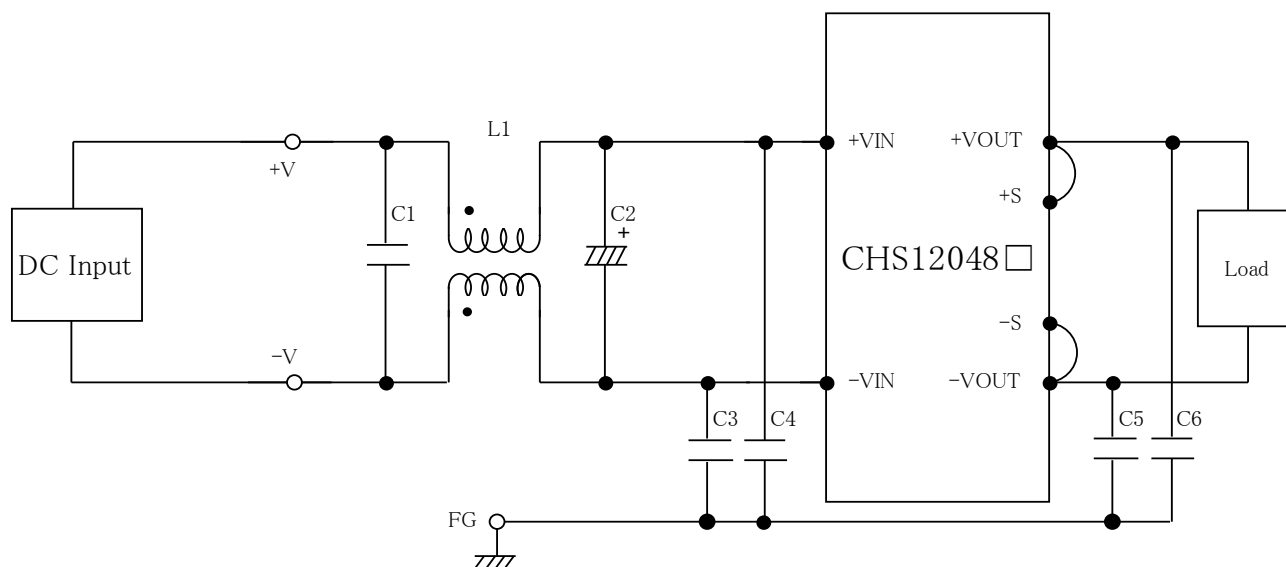


Fig.1 Testing circuitry

L1 : 1mH SC-05-10J (TOKIN)  
C1 : 250V 2.2  $\mu$ F FPD22E225J4 (NITSUKO)  
C2 : 100V 47  $\mu$ F PWseries (nichicon)  
C3,C4 : 630V 0.068  $\mu$ F FPD22J683J4 (NITSUKO)  
C5,C6 : 630V 0.033  $\mu$ F FPD22J333J4 (NITSUKO)